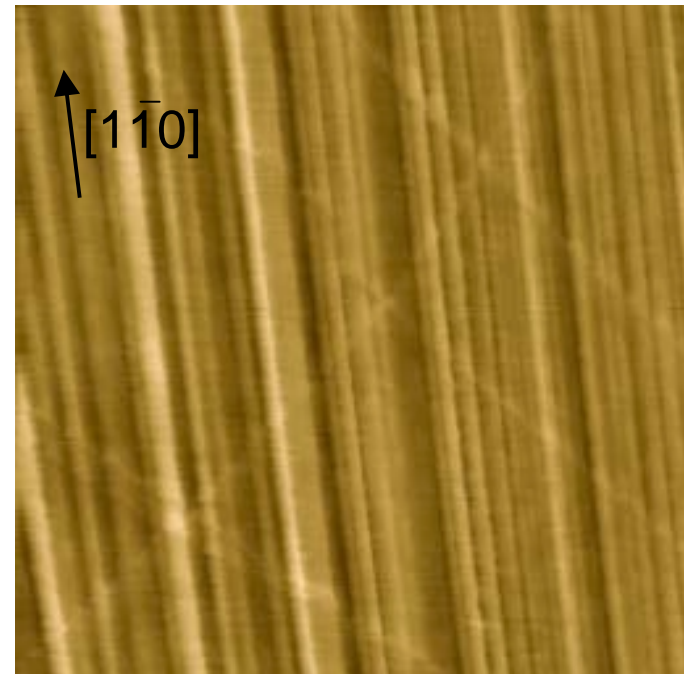
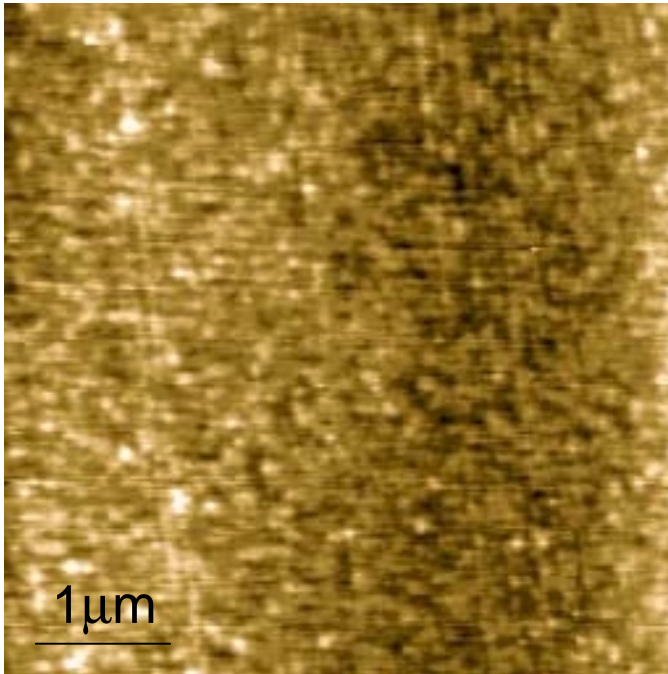


AFM images

$\text{In}_{0.75}\text{Ga}_{0.25}\text{As}$ (300 Å) / $\text{In}_{0.52}\text{Al}_{0.48}\text{As}$ / InP
structures

in-situ anneal



Surface roughening (cross-hatched pattern) is caused by increasing concentration of 60° as well as 90° misfit dislocations